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P/2699-26

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Toshikazu KITAJIMA et al. Date : August 27, 2003  
Serial No. : 10/624,871 Group Art Unit : ---  
Filed : July 21, 2003 Examiner : ---  
For : FILM THICKNESS MEASURING METHOD, RELATIVE DIELECTRIC  
CONSTANT MEASURING METHOD, FILM THICKNESS MEASURING  
APPARATUS, AND RELATIVE DIELECTRIC CONSTANT  
MEASURING APPARATUS

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Commissioner for Patents  
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SUBMISSION

Sir:

Submitted herewith is a copy of art together with a form listing the same for the convenience of the Examiner.

EXPRESS MAIL CERTIFICATE

I hereby certify that this correspondence is being deposited with the United States Postal Service as Express Mail Post Office to Addressee (mail label #EV342531422US) in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on August 27, 2003:

Cheryl Desvignes

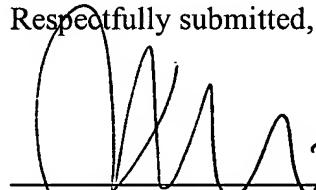
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Cheryl Desvignes  
Signature  
August 27, 2003

Date of Signature

JAF:lac

Respectfully submitted,

  
James A. Finder

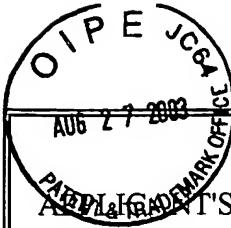
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<b>ART &amp; TRADEMARK'S ART CITATION</b> (Use several sheets if necessary)	Application 10/624,871	OFGS File No. P/2699-26
	Applicant Toshikazu KITAJIMA et al.	
	Filing Date July 21, 2003	Group Art Unit __

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
	US-5,475,319	12-1995	Hirae et al.	324	765	
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					

## FOREIGN PATENT DOCUMENTS

	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
	6-349920	12-1994	Japan (corresponds to U.S. Patent No. 5,475,319 listed above)				X

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


Examiner \_\_\_\_\_ Date Considered \_\_\_\_\_

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.